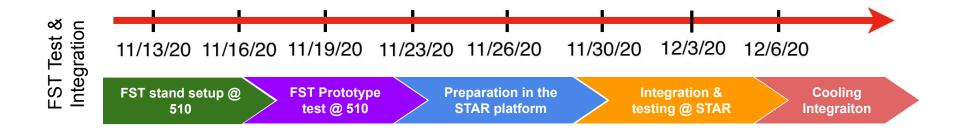




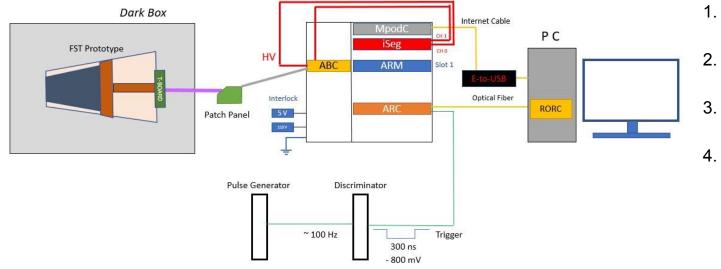
Report on FST Integration Test at BNL

For more info please visit: <u>https://drupal.star.bnl.gov/STAR/blog/ptribedy/fst-testing-bnl</u>

Yu Hu, Xu Sun, Prithwish Tribedy, Flemming Videbaek, Rahul Sharma



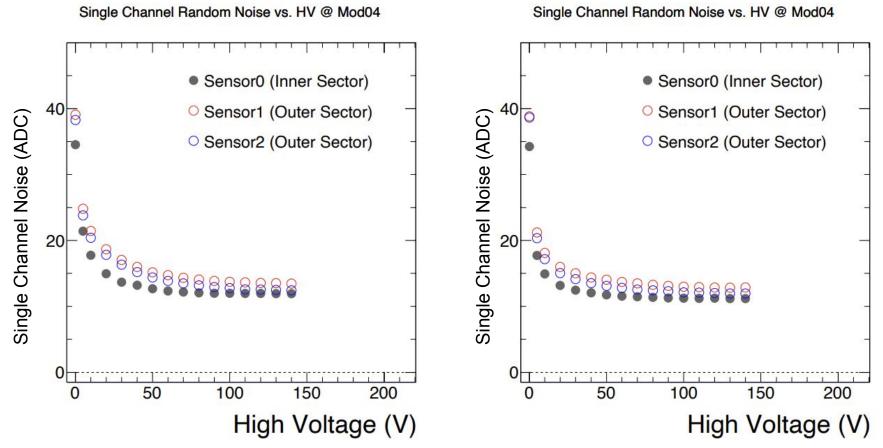
FST Prototype Test @ 510



- I. Noise test with/without grounding
- Noise test with different trigger rates
- Noise test with/withoutHV (0 V or 70 V)
- 4. Voltage scan (0 to 140 V)



HV Noise Scan Comparison

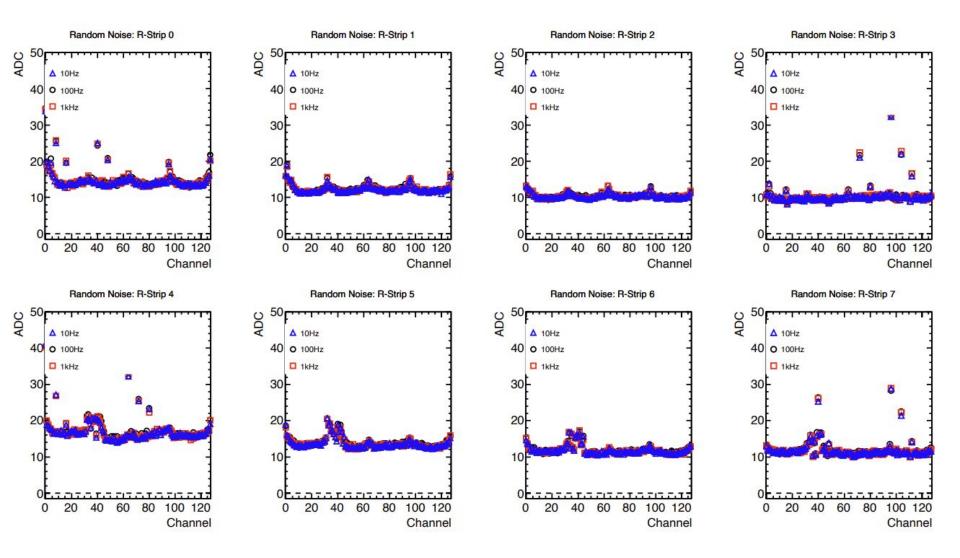


BNL @ 510

UIC

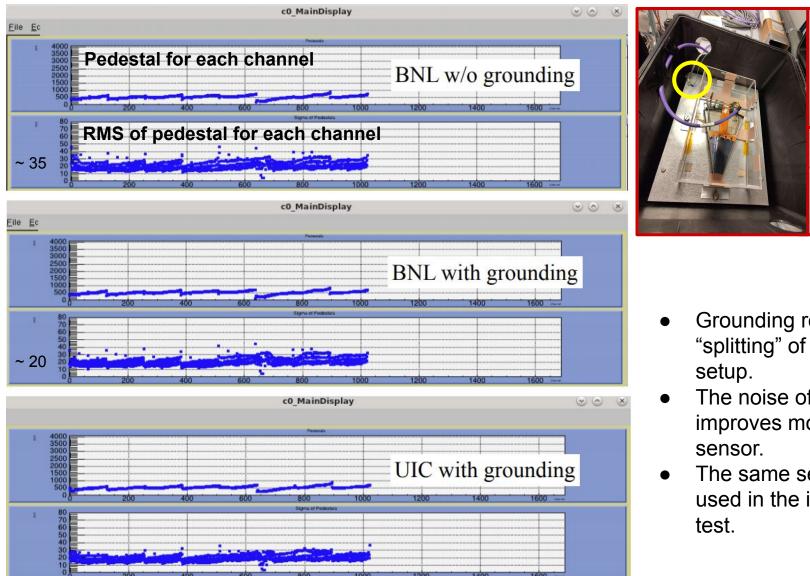
• Noise vs. HV shows the same structure & noise @ BNL is slightly higher than UIC

Noise with Different Trigger Rates



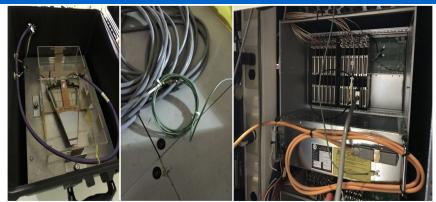
• Noise with different trigger rates (10Hz, 100Hz and 1kHz) show the same behavior

Noise Readout Test with/without Grounding

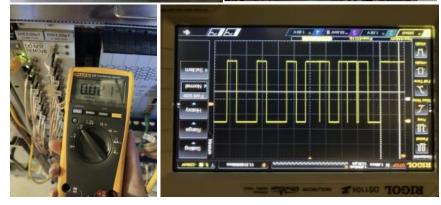


- Grounding reduce the "splitting" of noise at BNL
- The noise of inner sensor improves more than outer
- The same setup has been used in the integration

FST Prototype Integration Test @ STAR







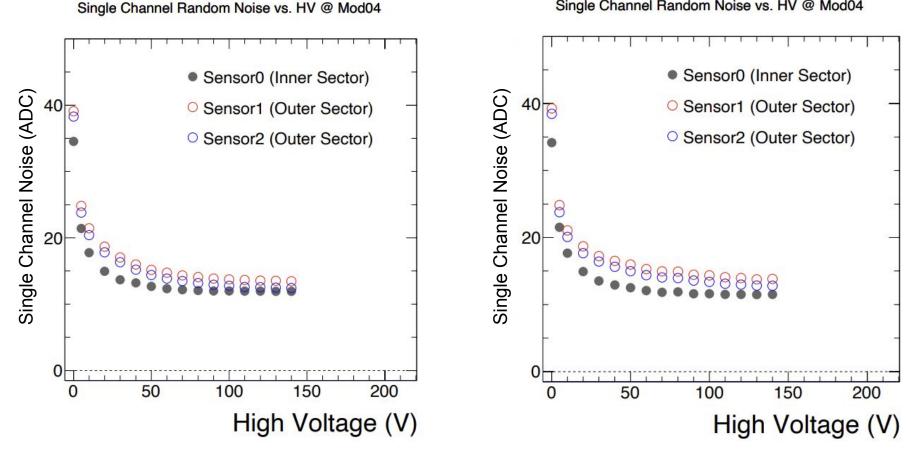
- Setup a dark box with FST module on 3rd floor and the grounding to FST crate #2. (with the help of Christian)
- Power up crate and test the fiber. Test Trigger/TCD interface and generate a bunch of events for us to have a look (with the help of Tonko and Gerard).
- Re-assigned IP address for FST MPOD01-03 (with the help of Wayne). Identify the PC (softioc4) for FST slow control and could operate FST Crate MPOD02 with the slow control scripts.
- Readout FST module & analysis the data. Did noise HV scan (0 V ~ 70 V) with STAR DAQ (with the standalone macro from Tonko)
- Adjust max HV to 150-155V for all for all ISEG modules in FST Crates.
- Finished the full noise HV scan with STAR DAQ (0 V ~ 140 V)
- Random trigger test with STAR DAQ
- FST DAQ integration test was a success.

Integration Test: HV Noise Scan

BNL @ 510

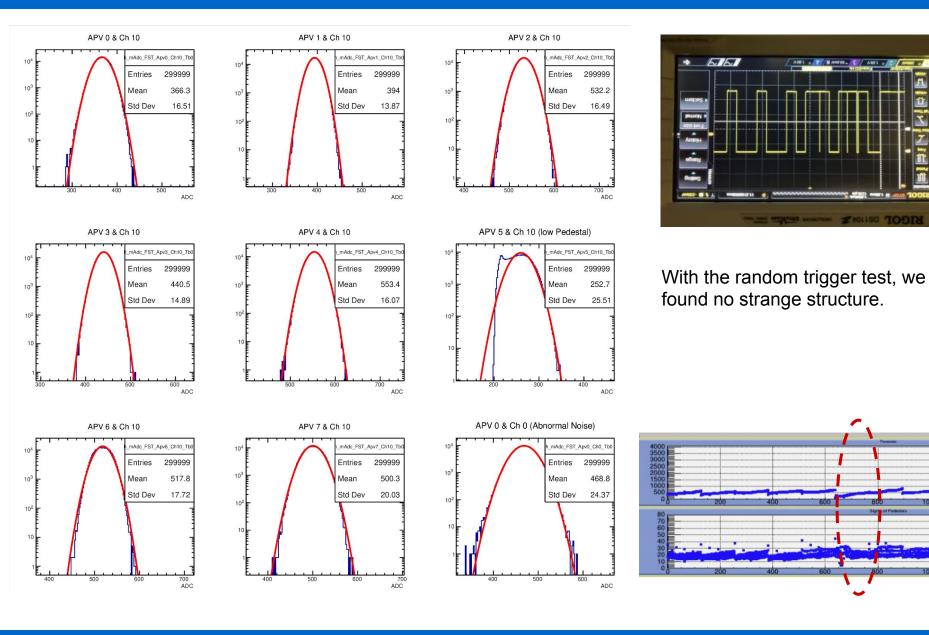
Integration Test @ STAR

Single Channel Random Noise vs. HV @ Mod04



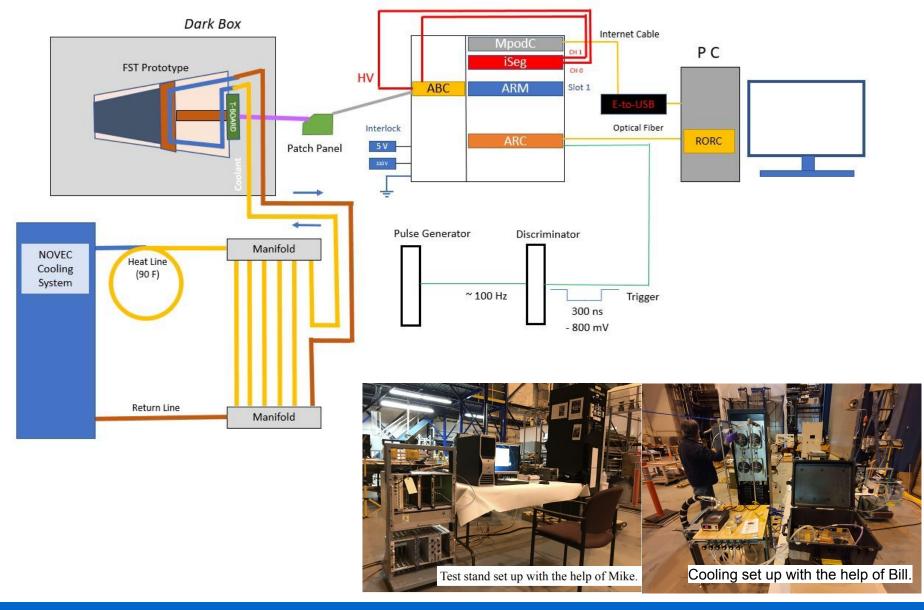
Noise vs. HV shows the same structure & noise in BNL Test Stand and STAR Integration Test.

Random Trigger Test

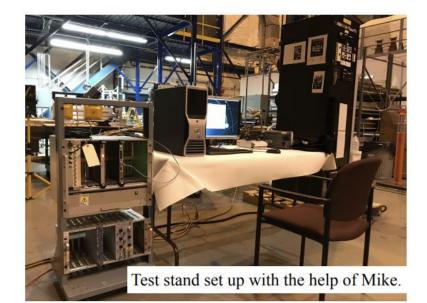


Z MOLISO TOOR

FST Cooling Integration Test



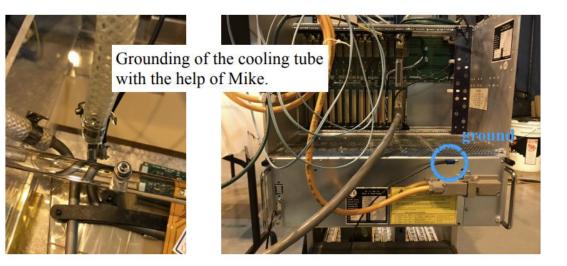
FST Cooling Integration Test





Cooling test stand set up with the help of Rahul & team. The tube used for supply is really hard to plug in.





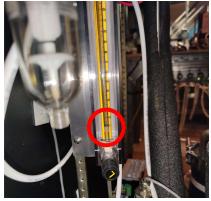


Link to the slides from last meeting: <u>https://drupal.star.bnl.gov/STAR/system/files/FstIntegrationTestDec07Dec13.pdf</u>

Cooling system





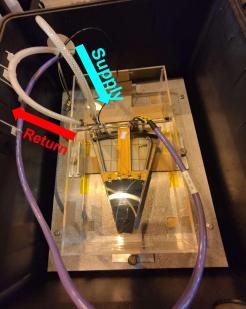


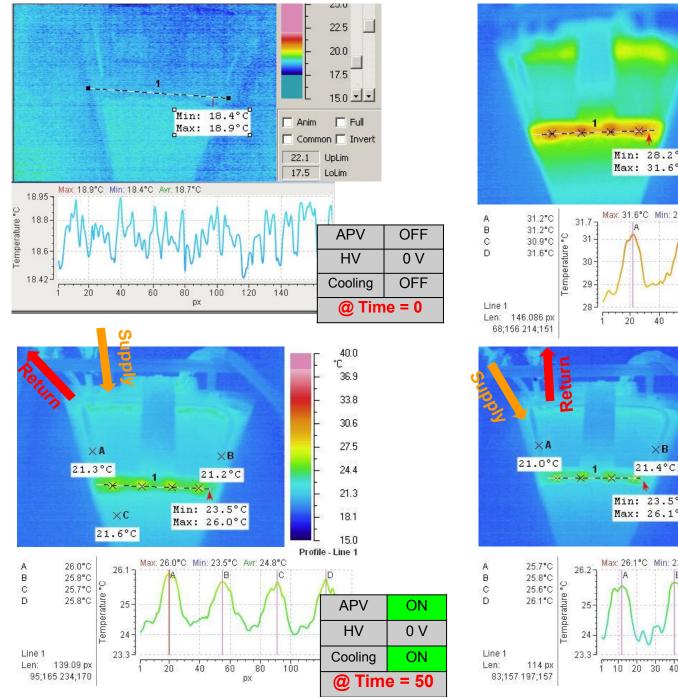


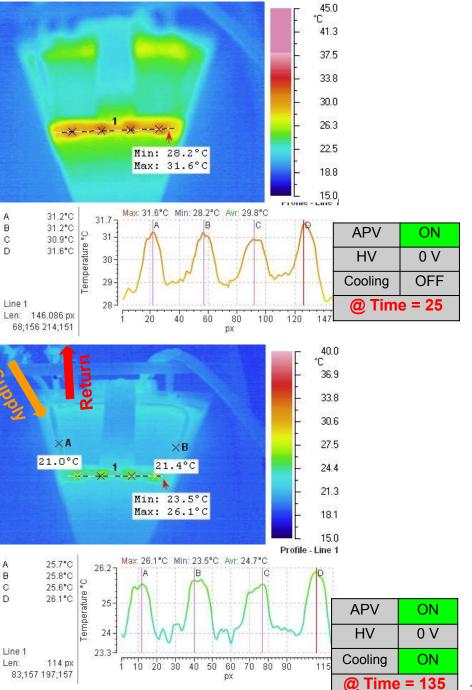
Cooling system:

- Setup proper grouding for the tubes
- Lowest flow we can set on crate: ~ 6 L/min
- 6 loops, we only use 1, other loops are idle, so the flow to our detector < 1 L/min</p>
- Use 2 clamps to avoid leak
- We see stable tank level, conjugate supply & return flow, 0 nitrogen gas flow
 --> No leak
- Supply tube: Tygon C-544-A I.B. (hard)
- Return tube: Tygon 3370 I.B. (soft)
- Tried maximum flow of ~6 L/min (closing other channels) to the prototype for short time, found no leak

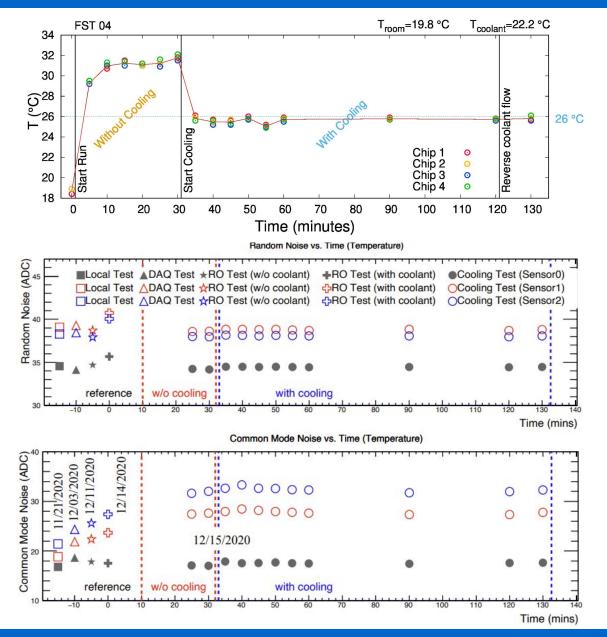








Cooling Efficiency Testing



- Sensors and other parts showed stable temperature no overheating
- About ~1 L/min flow speed, the cooling is already very efficient
- Reversing the coolant flow direction leads to no significant temperature difference for the APV chips
- Both random noise and CMN are stable within the temperature range 25-32 °C.
- The jump in the random noise of RO test is due to the light => we were taking the pictures while running.
- CMN builds up with time for outer sector?→Need to check FST04 with Fermi Lab test stand to verify the module performance.

Summary

FST DAQ integration test

- Noise vs. HV shows the same structure & noise
- Noise with different trigger rates (10Hz, 100Hz and 1kHz) show the same behavior
- We could control the HV with softioc4, collect the data with the "run control"
 - ▷ Complete & Success for FST DAQ Integration Test



FST Cooling test:

- The current setup showed with about ~1 L/min flow speed, the cooling is already very efficient
- Reversing the coolant flow direction leads to no significant temperature difference for the APV chips
- Both random noise and CMN(Common Mode Noise) are stable within the temperature range 25-32 °C.
- CMN raising with time for outer sector→Need a further check with FST04
 @ Fermi Lab test stand

▷ Complete & Success for FST Cooling Integration Test

